

<b>Notice of References Cited</b>	Application/Control No. 10/039,163	Applicant(s)/Patent Under Reexamination VOLTZ ET AL.	
	Examiner Greg Cunningham	Art Unit 2676	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-5,245,326 A	09-1993	Zalph, Walter N.	345/92
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	M	US-			

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	EP000780986A2	06-1997	Europe	Thomson	H03M1/10
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Analog Devices, ADV476 pages 1-12, disclosed bt Wynne in col. 5, line 64.
	V	
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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